- Flow-Through Architecture Optimizes **PCB Layout**
- Center-Pin V_{CC} and GND Pin Configurations **Minimize High-Speed Switching Noise**
- **EPIC™** (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic **Small-Outline Packages and Standard** Plastic 300-mil DIPs

description

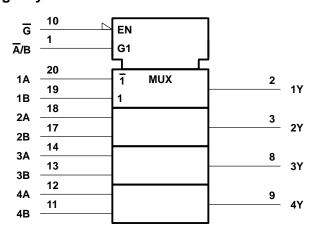
This data selector/multiplexer contains inverters and drivers to supply full data selection to the four output gates. A separate strobe (G) input is provided. A 4-bit word is selected from one of two sources and is routed to the four outputs. The 74AC11157 provides true data.

The 74AC11157 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

	INPU	JTS		OUTPUT
G	Ā/B	Α	В	Y
Н	Х	Χ	Χ	L
L	L	L	X	L
L	L	Н	X	Н
L	Н	Χ	L	L
L	Н	Χ	Н	Н

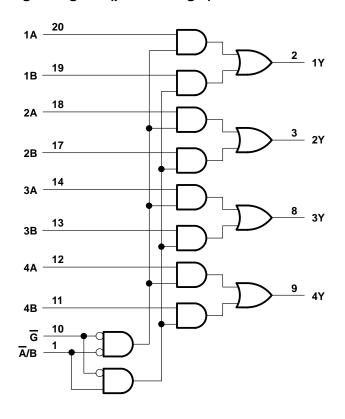
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

DW OR N PACKAGE (TOP VIEW) Ā/B Γ 20 1 1A 19 1B 1Υ **Π** 2Y 🛮 18 2A 3 GND 4 17 2B GND [16 VCC GND ∏ 15 VCC 14 🕇 3A GND 7 3Y 🛮 8 13 3B 4Y **∏** 12**∏** 4A 9 G 11 **1** 4B

logic diagram (positive logic)



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INSTRUMENTS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)	$5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Storage temperature range	. −65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 2)

			MIN	NOM	MAX	UNIT
Vcc	Supply voltage		3	5	5.5	V
		V _{CC} = 3 V	2.1			
V_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			V
		V _{CC} = 5.5 V	3.85			
		V _{CC} = 3 V		0.9	0.9	
V _{IL}	Low-level input voltage	V _{CC} = 4.5 V			1.35	V
		V _{CC} = 5.5 V			1.65	
٧ _I	Input voltage	·	0		VCC	V
٧o	Output voltage		0		VCC	V
		V _{CC} = 3 V			-4	
loh	High-level output current	V _{CC} = 4.5 V			-24	mA
		V _{CC} = 5.5 V			-24	
		V _{CC} = 3 V			12	
loL	Low-level output current	V _{CC} = 4.5 V			24	mA
		V _{CC} = 5.5 V			24	
Δt/Δν	Input transition rise or fall rate	-	0		10	ns/V
TA	Operating free-air temperature		-40		85	°C

NOTE 2: Unused or floating inputs must be held high or low.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS V		T/	A = 25°C	;	MIN	0.1 0.1 0.1 0.44 0.44 1.65 ±1 ±5 80	UNIT
PARAMETER	TEST CONDITIONS	vcc	MIN	TYP	MAX	IVIIIV		UNII
		3 V	2.9			2.9		
	I _{OH} = - 50 μA	4.5 V	4.4			4.4		
		5.5 V	5.4			5.4		
Voн	I _{OH} = -4 mA	3 V	2.58			2.48		V
	$I_{OL} = -24 \text{ mA}$ $I_{OH} = -75 \text{ mA}^{\dagger}$ 5.5	4.5 V	3.94			3.8		
	I _{OL} = – 24 mA	5.5 V	4.94			4.8		
	I _{OH} = -75 mA [†]	5.5 V				3.85		
	I _{OL} = 50 μA	3 V			0.1		0.1	
		4.5 V			0.1		0.1	
		5.5 V			0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.44	V
	1 04 mA	4.5 V			0.36		0.44	
	I _{OL} = 24 mA	5.5 V		-	0.36		0.44	
	I _{OL} = 75 mA [†]	5.5 V					1.65	
l _l	V _I = V _{CC} or GND	5.5 V			±0.1		±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±5	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΑ
C _i	$V_I = V_{CC}$ or GND	5 V		3.5				pF

T Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	T _A = 25°C			MIN	MAY	UNIT
	(INPUT)		MIN	TYP	MAX	IVIIIV	MAX	UNIT
^t PLH	A or B	Y	1.8	6.2	8.5	1.8	9.5	ns
tpHL			2.6	8.3	11.1	2.6	12.5	
^t PLH	Ā/B	V	1.9	6.8	8.9	1.9	10	ns
t _{PHL}		·	2.7	8.7	11.4	2.7	12.9	115
^t PLH	G	٧	1.6	6	8.6	1.6	9.2	
t _{PHL}	G	1	2.8	8.6	11.2	2.8	12.3	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	T _A = 25°C			MIN	MAX	UNIT
	(INPUT)		MIN	TYP	MAX	IVIIIN	WAA	ONT
^t PLH	A or B	V	1.5	3.9	5.8	1.5	6.4	ns
^t PHL		Ť	2.2	5.3	7.5	2.2	8.6	115
^t PLH	Ā/B	V	1.7	4.2	6.2	1.7	6.8	ns
^t PHL		ī	2.3	5.5	8	2.3	9	10
^t PLH	G	V	1.6	3.8	5.9	1.6	6.5	nc
^t PHL	G	ī	2.3	5.4	7.8	2.3	8.8	ns

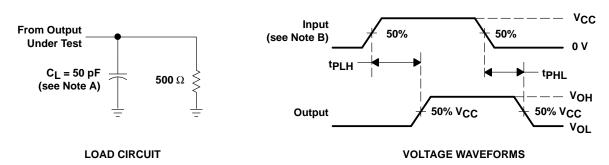


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operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	36	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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